











TPD1S514x

SLVSCF6E - APRIL 2014-REVISED OCTOBER 2015

TPD1S514x Family USB Charger Over Voltage, Surge and ESD Protection for V_{BUS} PIN

Features

- Over Voltage Protection at V_{BUS CON} up to 30-V DC
- Precision OVP (< ± 1% Tolerance)
- Low R_{ON} nFET Switch Supports Host and Charging Mode
- Dedicated V_{BUS POWER} Pin Offers Flexible Power up Options Under Dead Battery Condition
- Transient Protection for V_{BUS} Line:
 - IEC 61000-4-2 Contact Discharge ±15 kV
 - IEC 61000-4-2 Air Gap Discharge ±15 kV
 - IEC 61000-4-5 Open Circuit Voltage 100 V
 - Precision Clamp Circuit Limits the V_{BUS SYS} Voltage < V_{OVP}
- **USB Inrush Current Compliant**
- Thermal Shutdown (TSD) Feature

Applications

- Cell Phones
- **Tablets**
- eBook
- Portable Media Players
- 5-V, 9-V, and 12-V Power Rails

3 Description

The TPD1S514 Family consists of single-chip protection solutions for 5-V, 9-V or 12-V USB V_{BUS} lines, or other power buses. The bidirectional nFET switch ensures safe current flow in both charging and host mode while protecting the internal system circuits from any over voltage condition at the V_{BUS_CON} pin. On the V_{BUS_CON} pin, this device can handle over voltage protection up to 30-V DC. After the EN pin toggles low, any device in the TPD1S514 Family waits 20 ms before turning ON the nFET through a soft start delay.

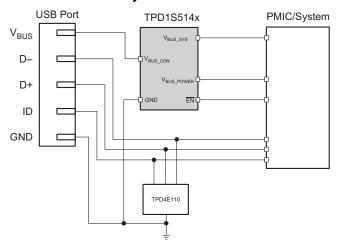
Typical application interfaces for the TPD1S514 Family are V_{BUS} lines in USB connectors typically found in cell phones, tablets, eBooks, and portable media players. The TPD1S514 Family can also be applied to any system using an interface for a 5-V, 9-V, or 12-V power rail.

Device Information⁽¹⁾

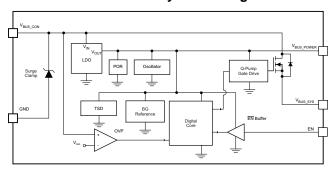
| DEVICE NAME | PACKAGE | BODY SIZE (NOM) |
|-------------|-----------|-------------------|
| TPD1S514x | WCSP (12) | 1.29 mm × 1.99 mm |

(1) For all available packages, see the orderable addendum at the end of the datasheet.

TPD1S514 Family Circuit Protection Scheme



TPD1S514 Family Block Diagram





| 1 | Га | h | ۵۱ | ∩ f | C | ٦n | tο | nte |
|---|----|---|----|------------|---|----|----|------|
| ı | ıa | v | 16 | v | | _ | LC | 11.5 |

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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

| Changes from Revision D (July 2015) to Revision E | Page |
|--|---------------------|
| Removed Preview status of TPD1S514-3 | 1 |
| • Changed Max value of I _{VBUS_SLEEP} PARAMETER for TPD1S514-3 (Preview) from | n 308 μA to 335 μA5 |
| Updated TEST CONDITIONS for T _{OFF_DELAY} PARAMETER | 8 |
| Changes from Revision C (July 2015) to Revision D | Page |
| Added TPD1S514 and TPD1S514-3 (Preview) | 1 |
| Changes from Revision B (September 2014) to Revision C | Page |
| Removed Previewed TPD1S514-3 and Programmability Features | 1 |
| Changes from Revision A (July 2014) to Revision B | Page |
| Changed Body size to fix rounding error. | 1 |
| Changes from Original (April 2014) to Revision A | Page |
| Removed Preview status of TPD1S514-2. | 1 |
| Updated Device Comparison table. | 3 |
| Updated Electrical Characteristics OVP Circuit table | 7 |

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5 Device Comparison Table

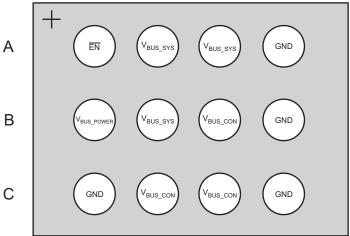
| TPD1S514 Family | V _{OVP} (V) | | V _{OVP_HYS} (mV) | V _{BUS_POWER} (V) ⁽¹⁾ | | T_Startup delay (ms) options | T_Soft Start (ms) options | | |
|-----------------|----------------------|-------|---------------------------|---|-----|------------------------------|---------------------------|-----|--|
| | Min | Тур | Max | Тур | Min | Тур | Тур | Тур | |
| TPD1S514-1 | 5.9 | 5.95 | 5.99 | 100 | 4.7 | 4.95 | | | |
| TPD1S514-2 | 9.9 | 9.98 | 10.05 | 100 | 4.7 | 4.95 | 20 | 3.5 | |
| TPD1S514-3 | 13.5 | 13.75 | 14 | 100 | 4.7 | 4.95 | 20 | 3.5 | |
| TPD1S514 | 5.9 | 5.95 | 5.99 | 20 | 6.2 | 6.48 | | | |

⁽¹⁾ With V_{BUS_CON} > 6.5V. See Sections V_{BUS_POWER}, TPD1S514-1, TPD1S514-2, TPD1S514-3 and V_{BUS_POWER}, TPD1S514 for full description.

6 Pin Configuration and Functions



1 2 0 7



Pin Functions

| PIN NAME NO. | | 1/0 | DESCRIPTION | | | | |
|------------------------|-----------------------------|-----|--|--|--|--|--|
| | | I/O | DESCRIPTION | | | | |
| EN A1 I | | 1 | nable Active-Low Input. Drive $\overline{\text{EN}}$ low to enable the switch. Drive $\overline{\text{EN}}$ high to disable the witch. | | | | |
| V _{BUS_POWER} | V _{BUS_POWER} B1 O | | 5-V Power source controlled by V _{BUS_CON} . | | | | |
| V _{BUS_SYS} | A2, A3, B2 | Ю | Connect to internal VBUS plane. | | | | |
| V _{BUS_CON} | B3, C2, C3 | Ю | Connect to USB connector VBUS pin; IEC 61000-4-2 ESD protection and IEC 61000-4-5 Surge protection. | | | | |
| GND | A4, B4, C1, C4 | G | Connect to PCB ground plane. | | | | |



7 Specifications

7.1 Absolute Maximum Ratings (1)(2)

over operating free-air temperature range (unless otherwise noted)

| | | | MIN | MAX | UNIT |
|------------------------|--|----------------------------|------|--------------------|------|
| V _{BUS_CON} | Supply voltage from USB connector | | -0.3 | 30 | V |
| V _{BUS_SYS} | Internal Supply DC voltage Rail on the PCB | | -0.3 | 20 | V |
| I _{BUS} | Continuous input current on V _{BUS_CON} pin ⁽³⁾ | | | 3.5 | Α |
| l _{out} | Continuous output current on V _{BUS_CON} pin ⁽³⁾ | | | 3.5 | Α |
| I _{PEAK} | Peak Input and Output Current on V _{BUS_CON} , V _{BUS_SYS} pin | n (10 ms) | | 8 | Α |
| I _{DIODE} | Continuous forward current through the FET body diode | | | 1 | Α |
| I _{POWER} | Continuous Current through V _{BUS_POWER} | | | 1 | mA |
| VEN | Voltage on Input pin (EN) | | | 7 | V |
| V _{BUS_POWER} | Continuous Voltage at V _{BUS_POWER} | TPD1S514-1 | | See ⁽⁴⁾ | V |
| | | TPD1S514-2 | | See ⁽⁴⁾ | |
| | | TPD1S514-3 | | See ⁽⁴⁾ | |
| | | TPD1S514 | | See ⁽⁴⁾ | |
| T _{STG} | Storage temperature range | | -65 | 150 | °C |
| T _A | Operating Free Air Temperature | | -40 | 85 | °C |
| | IEC 61000-4-5 Peak Pulse Current (t _p = 8/20µs) | V _{BUS_CON} pin | | 30 | Α |
| | IEC 61000-4-5 Peak Pulse Power (t _p = 8/20µs) | V _{BUS_CON} pin | | 900 | W |
| | IEC 61000-4-5 Open circuit voltage (t _p = 1.2/50 μs) | V _{BUS_CON} pin | | 100 | V |
| C _{LOAD} | Output load capacitance | V _{BUS_SYS} pin | 0.1 | 100 | μF |
| C _{CON} | Input capacitance | V _{BUS_CON} pin | 0.1 | 50 | μF |
| C _{POW} | V _{BUS_POWER} Capacitance | V _{BUS_POWER} pin | 0.1 | 4.7 | μF |

⁽¹⁾ Stresses above these ratings may cause permanent damage. Exposure to absolute maximum conditions for extended periods may degrade device reliability. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those specified is not implied.

- (2) The algebraic convention, whereby the most negative value is a minimum and the most positive value is a maximum.
- (3) Thermal limits and power dissipation limits must be observed.
- (4) 6.9 V or V_{BUS_CON} + 0.3 V, whichever is smaller.

7.2 ESD Ratings

| | | | | VALUE | UNIT |
|--------------------|-------------------------|--|--------------------------|--------|------|
| | | Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1) | | | |
| ., | | Charged-device model (CDM), per JEDEC spe | ±500 | ., | |
| V _(ESD) | Electrostatic discharge | IEC 61000-4-2 Contact Discharge | V _{BUS_CON} pin | ±15000 | V |
| | | IEC 61000-4-2 Air-gap Discharge V _{BUS_CON} pin | | ±15000 | |

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process. Manufacturing with less than 500-V HBM is possible with the necessary precautions.

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⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process. Manufacturing with less than 250-V CDM is possible with the necessary precautions.



7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

| | | | MIN | TYP | MAX | UNIT |
|----------------------|---|----------------------------|-----|-----|---|------|
| V _{BUS_CON} | Supply voltage from USB connector | TPD1S514-1 | 3.5 | 5 | 5.9 | V |
| | | TPD1S514-2 | 3.5 | 9 | 9.9 | |
| | | TPD1S514-3 | 3.5 | 12 | 13.5 | |
| | | TPD1S514 | 3.5 | 5 | 5.9 | |
| V _{BUS_SYS} | Internal Supply DC voltage Rail on the PCB Output load capacitance Input capacitance | TPD1S514-1 | 3.9 | 5 | 5.9 | V |
| | | TPD1S514-2 | 3.9 | 9 | 9.9 | |
| | | TPD1S514-3 | 3.9 | 12 | 13.5 | |
| | | TPD1S514 | 3.9 | 5 | 9.9 13.5 5.9 5.9 9.9 13.5 5.9 | |
| C _{LOAD} | Output load capacitance | V _{BUS_SYS} pin | | 2.2 | | μF |
| C _{CON} | Input capacitance | V _{BUS_CON} pin | | 1 | | μF |
| C _{POWER} | Capacitance on V _{BUS_POWER} | V _{BUS_POWER} pin | | 1 | | μF |
| T _A | Operating free-air temperature | | -40 | · | 85 | °C |

7.4 Thermal Information

| | | TPD1S514 Family | |
|----------------------|--|-----------------|------|
| | THERMAL METRIC ⁽¹⁾ | YZ (WCSP) | UNIT |
| | | 12 PINS | |
| $R_{\theta JA}$ | Junction-to-ambient thermal resistance | 89 | °C/W |
| $R_{\theta JC(top)}$ | Junction-to-case (top) thermal resistance | 0.6 | °C/W |
| $R_{\theta JB}$ | Junction-to-board thermal resistance | 16.3 | °C/W |
| ΨЈТ | Junction-to-top characterization parameter | 2.7 | °C/W |
| ΨЈВ | Junction-to-board characterization parameter | 16.2 | °C/W |

⁽¹⁾ For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

7.5 Supply Current Consumption

over operating free-air temperature range (unless otherwise noted)

| P | ARAMETER | TEST CO | NDITIONS | DEVICE NAME | TYP | MAX | UNIT |
|-----------------------|--|---|-----------------------------|-------------|-----|-----|------|
| | | | V _{BUS_CON} = 5 V | TPD1S514-1 | 150 | 245 | |
| | | Measured at V _{BUS CON} pin, | V _{BUS_CON} = 9 V | TPD1S514-2 | 176 | 281 | |
| VBUS_SLEEP | | <u>EN</u> = 5 V | V _{BUS_CON} = 12 V | TPD1S514-3 | 195 | 335 | μA |
| | V _{BUS CON} Operating | | V _{BUS_CON} = 5 V | TPD1S514 | 150 | 245 | |
| | Current Consumption | | V _{BUS_CON} = 5 V | TPD1S514-1 | 228 | 354 | |
| | | Measured at V _{BUS_CON} pin, | V _{BUS_CON} = 9 V | TPD1S514-2 | 250 | 413 | |
| I _{VBUS} | | EN = 0 V and no load | V _{BUS_CON} = 12 V | TPD1S514-3 | 270 | 456 | μA |
| | | | V _{BUS_CON} = 5 V | TPD1S514 | 228 | 354 | |
| | | Measured at V _{BUS_SYS} pin, V _{BUS_CON} = Hi-Z, EN = 0 V | V _{BUS_SYS} = 5 V | TPD1S514-1 | 210 | 354 | μА |
| | V _{BUS SYS} Operating Current | | V _{BUS_SYS} = 9 V | TPD1S514-2 | 250 | 424 | |
| I _{VBUS_SYS} | Consumption | | V _{BUS_SYS} = 12 V | TPD1S514-3 | 333 | 461 | |
| | | | V _{BUS_SYS} = 5 V | TPD1S514 | 210 | 354 | |
| | | | V _{BUS_SYS} = 5 V | TPD1S514-1 | 90 | 218 | |
| | Host Mode Leakage | Measured at V _{BUS_SYS} pin, | V _{BUS_SYS} = 9 V | TPD1S514-2 | 290 | 491 | μA |
| IHOST_LEAK | current | $V_{BUS_CON} = Hi-Z, EN = 5 V$ | V _{BUS_SYS} = 12 V | TPD1S514-3 | 506 | 696 | |
| | | | V _{BUS_SYS} = 5 V | TPD1S514 | 90 | 218 | |



7.6 Electrical Characteristics EN Pin

over operating free-air temperature range (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT | | | |
|-----------------|--------------------------|-----------------|---|-----|-----|------|----|--|--|
| V _{IH} | High-level input voltage | EN | V _{BUS_CON} = 5 V | 1.2 | | 6 | V | | |
| V_{IL} | Low-level input voltage | EN | V _{BUS_CON} = 5 V | 0 | | 0.8 | V | | |
| I _{IL} | Input Leakage Current | EN | $V_{\overline{EN}} = 0 \text{ V}, V_{BUS_CON} = 5 \text{ V}$ | | | 1 | μΑ | | |
| I _{IH} | Input Leakage Current | EN | $V_{\overline{EN}} = 5 \text{ V}, V_{BUS CON} = 5 \text{ V}$ | | | 10 | μA | | |

7.7 Thermal Shutdown Feature

over operating free-air temperature range (unless otherwise noted)

| | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-------------------|-------------------|--|-----|-----|-----|------|
| T _{SHDN} | Thermal Shutdown | V _{BUS_CON} = 5 V, EN = 0 V, Junction temperature decreases from thermal shutdown level until the nFET switch turns off. | | 145 | | °C |
| Thermal Sh | utdown Hysteresis | V _{BUS_CON} = 5 V, EN = 0 V, Junction temperature decreases from thermal shutdown level until the nFET switch turns on. | | 25 | | °C |

7.8 Electrical Characteristics nFET Switch

 $T = 25^{\circ}C$

| | PARAMETER | TEST COND | ITIONS | MIN | TYP | MAX | UNIT |
|--------------------------|---|--|------------|-----|-----|-----|-------|
| D. Origin ON Designation | $V_{BUS_CON} = 5 \text{ V}, I_{OUT} = 1 \text{ A}$ | TPD1S514-1 | | 39 | 50 | | |
| | Switch ON Resistance | $V_{BUS_CON} = 9 \text{ V}, I_{OUT} = 1 \text{ A}$ | TPD1S514-2 | | 39 | 50 | mΩ |
| R _{ON} | Switch On Resistance | $V_{BUS_CON} = 12 \text{ V}, I_{OUT} = 1 \text{ A}$ | TPD1S514-3 | | 39 | 50 | 11122 |
| | | $V_{BUS_CON} = 5 \text{ V}, I_{OUT} = 1 \text{ A}$ | TPD1S514 | | 39 | 50 | |



7.9 Electrical Characteristics OVP Circuit

T = 25°C

| | PARAMETER | | TEST C | ONDITIONS | MIN | TYP | MAX | UNIT |
|-------------------------------|--|----------------------|---|---------------------|------|-------|-------|------|
| | | | | TPD1S514-1 | 5.90 | 5.95 | 5.99 | |
| V | Input voltage protection | V | V _{BUS CON} increasing | TPD1S514-2 | 9.9 | 9.98 | 10.05 | \/ |
| V _{OVP} | threshold | V _{BUS_CON} | from 0 V to 20 V | TPD1S514-3 | 13.5 | 13.75 | 14 | V |
| | | | | TPD1S514 | 5.90 | 5.95 | 5.99 | |
| | | | | TPD1S514-1 | | 100 | | |
| V _{HYS_OVP} | Hysteresis on OVP | V _{BUS_CON} | V _{BUS_CON} decreasing from 20 V to 0 V | TPD1S514-2 | | 100 | | |
| | | | | TPD1S514-3 | | 100 | | mV |
| | | | | TPD1S514 | | 20 | | |
| V _{UVLO} | Input under voltage lockout | V _{BUS_CON} | V _{BUS CON} voltage rising from 0 V to 5 V | | 2.7 | 3.1 | 3.5 | V |
| V _{HYS_UVLO} | Hysteresis on UVLO | V _{BUS_CON} | Difference between risir thresholds | ng and falling UVLO | | 80 | | mV |
| V _{UVLO_FALLING} | Input under voltage lockout | V _{BUS_CON} | V _{BUS_CON} voltage falling | from 5 V to 0 V | 2.6 | 3.0 | 3.4 | V |
| V _{UVLO_SYS} | V _{BUS_SYS} under voltage lockout | V _{BUS_SYS} | V _{BUS_SYS} voltage rising | from 0 V to 5 V | 2.8 | 3.7 | 4.3 | V |
| V _{HYS_UVLO_SYS} | V _{BUS_SYS} UVLO Hysteresis | V _{BUS_SYS} | Difference between risir thresholds on V _{BUS_SYS} | ng and falling UVLO | | 500 | | mV |
| V _{UVLO_SYS_FALLING} | V _{BUS_SYS} under voltage lockout | V _{BUS_SYS} | V _{BUS_SYS} voltage falling | from 5 V to 0 V | 2.6 | 3.0 | 3.4 | V |

7.10 Electrical Characteristics V_{BUS_POWER} Circuit

over operating free-air temperature range (unless otherwise noted)

| | PARAMETER | TEST | CONDITIONS | MIN | TYP | MAX | UNIT |
|----------------------------|--|---|------------|-----|------|------|------|
| | | | TPD1S514-1 | | 5.0 | 5.5 | |
| V _{CLAMP} Out | Output Valtage on V | V 20 V | TPD1S514-2 | | 5.0 | 5.5 | V |
| | Output Voltage on V _{BUS_POWER} during OVP | $V_{BUS_CON} = 20 \text{ V}$ | TPD1S514-3 | | 5.0 | 5.5 | |
| | | | TPD1S514 | | 6.48 | 6.68 | |
| | | V _{BUS_CON} = 5 V, I _{BUS_POWER} = 1 mA; | TPD1S514-1 | 4.7 | 4.95 | | |
| V | Output Voltage on V _{BUS POWER} during normal | | TPD1S514-2 | 4.7 | 4.95 | | V |
| V _{BUS_POWER} | operation | | TPD1S514-3 | 4.7 | 4.95 | | V |
| | | | TPD1S514 | 4.7 | 4.98 | | |
| I _{BUS_POWER_MAX} | Output Current on V _{BUS_POWER} | V _{BUS_CON} = 5 V - 15 V | , | | | 3 | mA |



7.11 Timing Requirements

over operating free-air temperature range (unless otherwise noted)

| | PARAMETER | TEST CONDI | TIONS | MIN | TYP | MAX | UNIT |
|---------------------------|---|--|----------------------------|------------|-----|-----|------|
| | | | TPD1S514-1 | | | | |
| | USB Charging Turn-ON | Measured from EN asserted LOW | TPD1S514-2 | | | | |
| t _{DELAY} | Delay | to nFET begins to Turn ON, excludes soft-start time | TPD1S514-3 | | 20 | | ms |
| | | | TPD1S514 | | | | |
| | | Force 5 V on VBUS CON. | | TPD1S514-1 | | | |
| | USB Charging rise time (Soft Start Delay) | measured from V _{BUS SYS} rises | TPD1S514-2 | 3.5 | | mo | |
| LSS | | from 10% to 90% (with 1 M Ω load/ | TPD1S514-3 | | | | ms |
| | | NO C _{LOAD}) | TPD1S514 | | | | |
| | | Managered from EN accorded Link | TPD1S514-1 | | | | |
| _ | USB Charging Turn-OFF | Measured from EN asserted High to V _{BUS SYS} falling to 10% with | TPD1S514-2 | | | | |
| toff_delay | time | $R_{LOAD} = 10 \Omega$ and No C_{LOAD} on | TPD1S514-3 | | 5.5 | | μs |
| | | V _{BUS_SYS} | TPD1S514 | | | | |
| OVER VOLTA | AGE PROTECTION | | | | | , | |
| t _{OVP_response} | OVP Response time | Measured from OVP Condition to F | ET Turn OFF ⁽¹⁾ | | | 100 | ns |

(1) Specified by design, not production tested

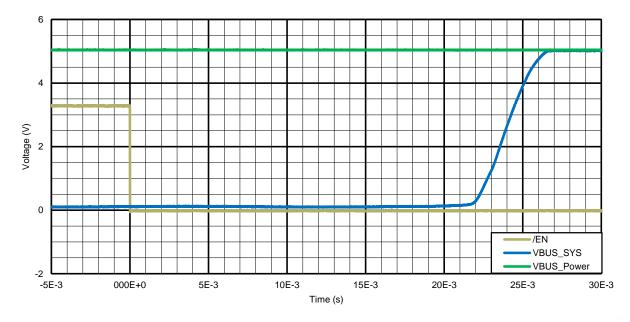


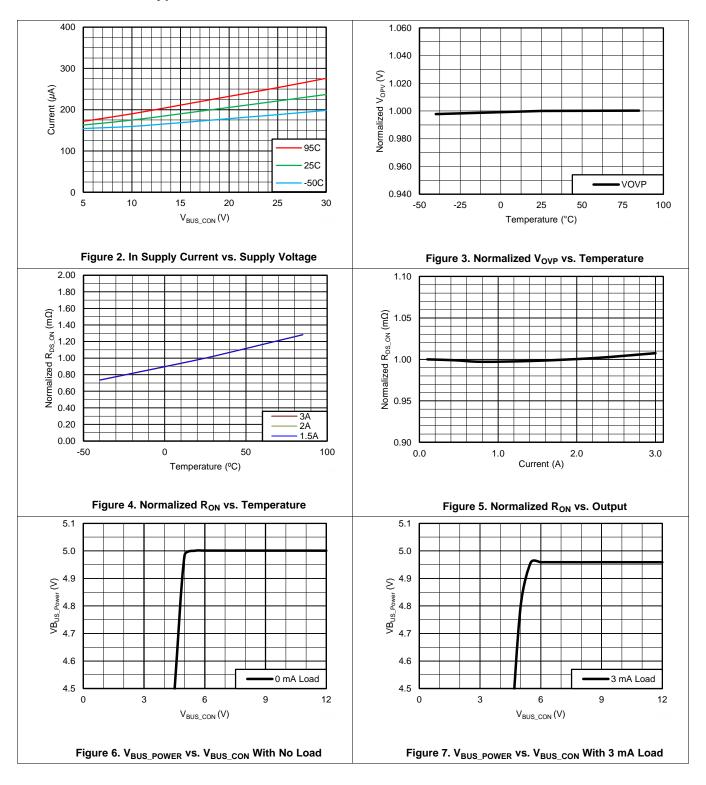
Figure 1. TPD1S514-1 Response to set EN low

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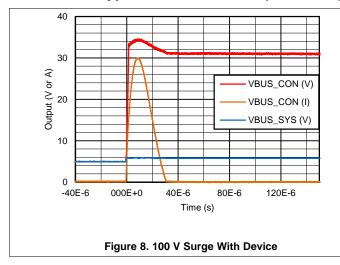
7.12 TPD1S514-1 Typical Characteristics



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TPD1S514-1 Typical Characteristics (continued)



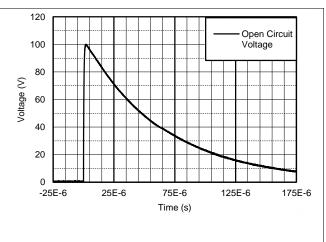


Figure 9. 100 V Surge Without Device

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8 Detailed Description

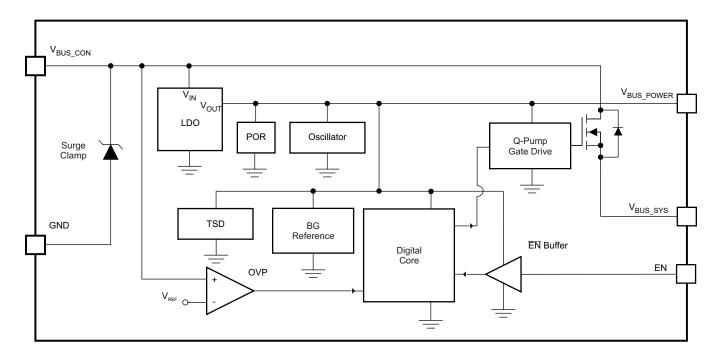
8.1 Overview

The TPD1S514 Family provides single-chip ESD, surge, and over voltage protection solutions for portable USB Charging and Host interfaces. Each device offers over voltage protection at the V_{BUS_CON} pin up to 30-V DC. The TPD1S514 Family offers an ESD and Precision Clamp for the V_{BUS_CON} pin, thus eliminating the need for external TVS clamp circuits in the application.

Each device has an internal oscillator and charge pump which controls turning ON the internal nFET switch. The internal oscillator controls the timers which enable the charge pump. If V_{BUS_CON} is less than V_{OVP} , the internal charge pump is enabled. After a 20 ms internal delay, the charge-pump starts-up, and turns ON the internal nFET switch through a soft start. If at any time V_{BUS_CON} rises above V_{OVP} , the nFET switch is turned OFF within 100 ns.

The TPD1S514 Family of devices also have a V_{BUS_POWER} pin which follows V_{BUS_CON} up to 4.9 V at 3 mA (except for TPD1S514, which follows V_{BUS_CON} up to 6.48 V, after which it is regulated to that voltage) to power the system from V_{BUS_CON} . In the case where the system battery state cannot power the system, voltage from an external charger can be provided to power the system. V_{BUS_POWER} is supplied by an always on LDO regulator supplied by V_{BUS_CON} . V_{BUS_POWER} output voltage remains regulated to 4.9 V (except for TPD1S514, which follows V_{BUS_CON} up to 6.48 V, after which it is regulated to that voltage) at up to 30-V DC on V_{BUS_CON} and during IEC 61000-4-5 surge events of up to 100 V open circuit voltage on V_{BUS_CON} .

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Over Voltage Protection on V_{BUS CON} up to 30 V DC

When the V_{BUS_CON} voltage rises above V_{OVP} , the internal nFET switch is turned OFF, removing power from the system side. V_{BUS_CON} can tolerate up to 30-V DC. The response to over voltage is very rapid, with the nFET switch turning off in less than 100 ns. When the V_{BUS_CON} voltage returns back to below $V_{OVP} - V_{HYS_OVP}$, the nFET switch is turned ON again after an internal delay of t_{OVP_RECOV} (t_{DELAY}). This time delay ensures that the V_{BUS_CON} supply has stabilized before turning the switch back on. After t_{OVP_RECOV} , the TPD1S514 Family device turns on the nFET through a soft start. Once the OVP condition is cleared the nFET is turned completely ON.

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Feature Description (continued)

8.3.2 Precision OVP (< ±1% Tolerance)

1% OVP trip threshold accuracy allows use of the entire input charging range while protecting sensitive systemside components from over voltage conditions.

8.3.3 Low R_{ON} nFET Switch Supports Host and Charging Mode

The nFET switch has a total on resistance (R_{ON}) of 39 mΩ. This equates to a voltage drop of less than 140 mV when charging at the maximum 3.5 A current level. Such low RON helps provide maximum potential to the system as provided by an external charger or by the system when in Host Mode.

8.3.4 V_{BUS POWER}, TPD1S514-1, TPD1S514-2, TPD1S514-3

The V_{BUS POWER} pin provides up to 3 mA and 5 V for powering the system using V_{BUS CON}. V_{BUS POWER} follows V_{BUS CON} after 3.5 V and up to the regulated 5 V. In the case where the system battery state cannot power the system, voltage from an external charger can power the system. V_{BUS POWER} is supplied by an always on LDO regulator supplied by V_{BUS CON}. The V_{BUS POWER} output voltage remains regulated to 5 V at up to 30-V DC on V_{BUS CON} and during IEC 61000-4-5 surge events of up to 100 V.

8.3.5 V_{BUS POWER}, TPD1S514

The V_{BUS POWER} pin provides up to 3 mA and 6.48 V for powering the system using V_{BUS_CON}. V_{BUS_POWER} follows V_{BUS CON} after 3.5 V and up to the regulated 6.48 V. In the case where the system battery state cannot power the system, voltage from an external charger can be provided to power the system. V_{BUS POWER} is supplied by an always on LDO regulator supplied by V_{BUS CON}. The V_{BUS POWER} output voltage remains regulated to 6.48 V at up to 30-V DC on $V_{BUS\ CON}$ and during IEC 61000-4-5 surge events of up to 100 V.

8.3.6 Powering the System When Battery is Discharged

There are two methods for powering the system under a dead battery condition. Case 1: The EN pin can be tied to ground so that the nFET is always ON (when V_{UVLO} < V_{BUS CON} < V_{OVP}) and an external charger can power V_{BUS}. Case 2: If EN is controlled by a Power Management Unit (PMIC) or other logic, V_{BUS POWER} can be used to power the PMIC. In Case 2, once the device is enabled, t_{DELAY} + t_{SS}, work together to meet the USB Inrush Current compliance.

8.3.7 ±15 kV IEC 61000-4-2 Level 4 ESD Protection

The V_{BUS CON} pin can withstand ESD events up to ±15 kV Contact and Air-Gap. An ESD clamp diverts the current to ground.

8.3.8 100 V IEC 61000-4-5 µs Surge Protection

The V_{BUS CON} pin can withstand surge events up to 100 V open circuit voltage (V_{PP}), or 900 W. A Precision Clamp diverts the current to ground and active circuitry switches OFF the nFET earlier than 100 ns before an over voltage can get through to V_{BYS SYS}. The ultra-fast response time of the TPD1S514 Family holds the voltage on V_{BUS SYS} to less than V_{OVP} during surge events of up to 100 V_{PP}.

8.3.9 Startup and OVP Recovery Delay

Upon startup or recovering from an over voltage, the TPD1S514 Family of devices have a built in startup delay. An internal oscillator controls a charge pump to control the delay. Once a manufactured pre-programmed time, t_{DELAY}, has elapsed, the charge pump is enabled which turns ON the nFET. A manufactured pre-programmed soft start, tss, is used when turning ON the nFET. Once the device is enabled, these start delays, t_{DFLAY} + t_{SS}, work together to meet the USB Inrush Current compliance.

8.3.10 Thermal Shutdown

The TPD1S514 Family has an over-temperature protection circuit to protect against system faults or improper use. The basic function of the thermal shutdown (TSD) circuit is to sense when the junction temperature has exceeded the absolute maximum rating and shuts down the device until the junction temperature has cooled to a safe level.

Product Folder Links: TPD1S514x

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8.4 Device Functional Modes

8.4.1 Operation With $V_{BUS CON} < 3.5 \text{ V}$ (Minimum $V_{BUS CON}$)

The TPD1S514 Family operates normally (nFET ON) with input voltages above 3.5 V. The maximum UVLO voltage is 3.5 V and the device will operate at input voltages above 3.5 V. The typical UVLO voltage is 3.1 V and the device may operate at input voltages above that point. The device may also operate at input voltages as low as 2.7 V, the minimum UVLO. At input voltages between 0.6 V and 1.2 V, the state of output pins may not be controlled internally.

8.4.2 Operation With V_{BUS CON} > V_{OVP}

The TPD1S514 Family operates normally (nFET ON) with input voltages below V_{OVP_min} . The typical OVP voltage is V_{OVP_TYP} and the device may operate at input voltages below that point. The device may also operate at input voltages as high as V_{OVP_MAX} .

| Device Name | | V _{OVP} | | | | | | | |
|-------------|------|------------------|-------|--|--|--|--|--|--|
| | MIN | TYP | MAX | | | | | | |
| TPD1S514-1 | 5.9 | 5.95 | 5.99 | | | | | | |
| TPD1S514-2 | 9.9 | 9.98 | 10.05 | | | | | | |
| TPD1S514-3 | 13.5 | 13.75 | 14 | | | | | | |
| TPD1S514 | 5.9 | 5.95 | 5.99 | | | | | | |

8.4.3 OTG Mode

The TPD1S514 Family of devices UVLO and OVP voltages are referenced to V_{BUS_CON} voltage. In OTG mode, V_{BUS_SYS} is driving the V_{BUS_CON} . Under this situation, initially V_{BUS_CON} is powered through the body diode of the nFET by V_{BUS_SYS} . Once the UVLO threshold on V_{BUS_CON} is met, the nFET turns ON. If there is a short to ground on V_{BUS_CON} the OTG supply is expected to limit the current.



Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The TPD1S514 Family of devices offer V_{BUS} port protection implementing UVLO and OVP, with an LDO supplied V_{BUS POWER} pin to regulate an output supply pin of 3 mA at 5 V (except for TPD1S514, which follows V_{BUS CON} up to 6.48 V, after which it is regulated to that voltage). The V_{BUS POWER} pin can be used to power the system from an external source on V_{BUS CON} in case the system's battery state cannot power the system.

9.2 Typical Application

9.2.1 TPD1S514-1 USB 2.0/3.0 Case 1: Always Enabled

The $\overline{\text{EN}}$ pin can be tied to ground so that the nFET is ON when $V_{\text{UVLO}} < V_{\text{BUS_CON}} < V_{\text{OVP}}$ and an external charger can power V_{BUS}. V_{BUS} POWER should be tied to ground with a 1-µF capacitor for LDO stability. USB Inrush Current compliance tests will need to be handled by the rest of the system since the start delays to the system since the system since the start delays to the system since the start delays to the system since t and t_{SS} implement only after the device changes from disabled to enabled, or after any UVLO or OVP event.

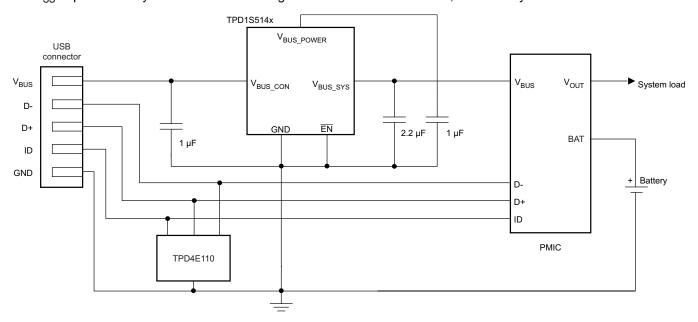


Figure 10. Always on, TPD1S514-1

9.2.1.1 Design Requirements

For this example, use the following table as input parameters:

| Design Parameters | Example Value |
|--------------------------------------|----------------------------|
| Signal range on V _{BUS_CON} | 3.5 V – 5.9 V |
| Signal range on V _{BUS_SYS} | 3.9 V – 5.9 V |
| Signal on EN | Tie to system ground plane |

Submit Documentation Feedback



9.2.1.2 Detailed Design Procedure

To begin the design process the designer needs to know the V_{BUS} voltage range.

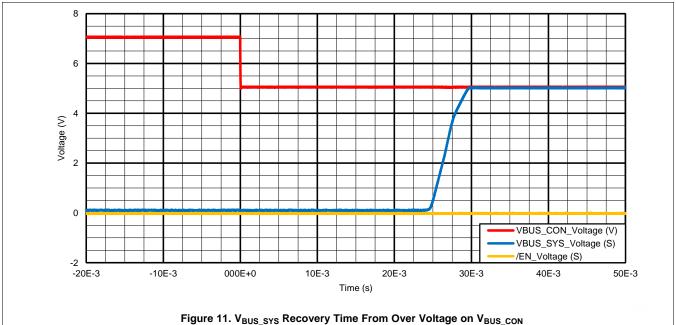
9.2.1.2.1 V_{BUS} Voltage Range

The UVLO trip-point is a maximum 3.5 V and the OVP trip-point is a minimum 5.9 V. This provides some headroom for the USB 2.0 specified minimum 4.4 V (Low-power) or 4.75 V (Full-power) and 5.25 V maximum; or the USB 3.0 specified minimum 4.45 V and 5.25 V maximum.

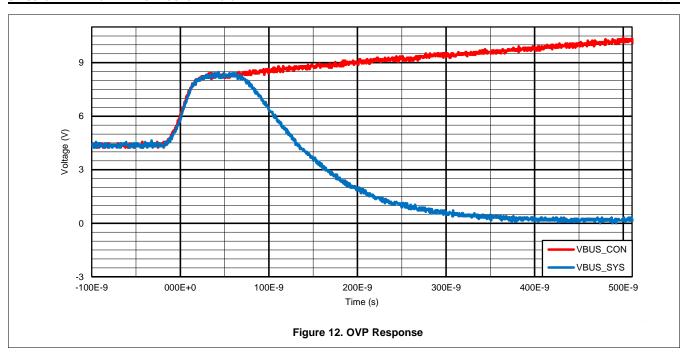
9.2.1.2.2 Discharged Battery

Connecting EN to ground sets the part active at all times. OVP and UVLO are always active, even when the system battery is fully discharged. In the case of a discharged system battery, V_{BUS SYS} can be used to power the system when a source with voltage between V_{IIVI O} and V_{OVP} is attached to V_{BUS CON}.

9.2.1.3 Application Curves









9.2.2 TPD1S514-1 USB 2.0/3.0 Case 2: PMIC Controlled EN

The TPD1S514 Family offers more flexibility to system designers to power up the system during a dead battery condition. Refer to Figure 13, the V_{BUS_POWER} pin supplies 4.95 V and 3 mA to power the PMIC in a dead battery condition. Regardless of \overline{EN} state, V_{BUS_POWER} is available to the PMIC. Utilizing this power, the PMIC can enable the TPD1S514 Family of devices when a valid V_{BUS_CON} voltage is present.

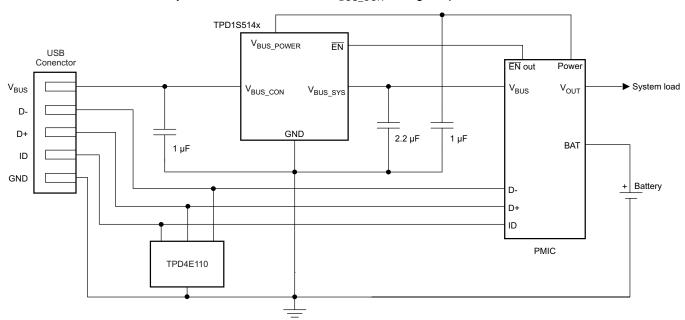


Figure 13. PMIC Controlled EN, TPD1S514-1

9.2.2.1 Design Requirements

For this example, use the following table as input parameters:

| Design Parameters | Example Value |
|--------------------------------------|---------------|
| Signal range on V _{BUS_CON} | 3.5 V – 5.9 V |
| Signal range on V _{BUS_SYS} | 3.9 V – 5.9 V |
| Drive EN low (enabled) | 0 V – 0.8 V |
| Drive EN high (disabled) | 1.2 V – 6.0 V |

9.2.2.2 Detailed Design Procedure

To begin the design process, some parameters must be decided upon. The designer needs to know the following:

- V_{BUS} voltage range
- PMIC power requirement

9.2.2.2.1 V_{BUS} Voltage Range

The UVLO trip-point is a maximum 3.5 V and the OVP trip-point is a minimum 5.9 V. This provides some headroom for the USB 2.0 specified minimum 4.4 V (Low-power) or 4.75 V (Full-power) and 5.25 V maximum; or the USB 3.0 specified minimum 4.45 V and 5.25 V maximum.

9.2.2.2.2 PMIC Power Requirement

The V_{BUS_POWER} pin can source up to 3 mA of current and maintain a minimum 4.8 V, 4.95 V typical. TPD1S514-1 design provides an LDO regulator supplied voltage source which can be used to provide power to a PMIC when its internal battery supplied power is unavailable. When selecting a matching PMIC, ensure its power requirement can be met by the V_{BUS_POWER} pin if designing for this scenario.

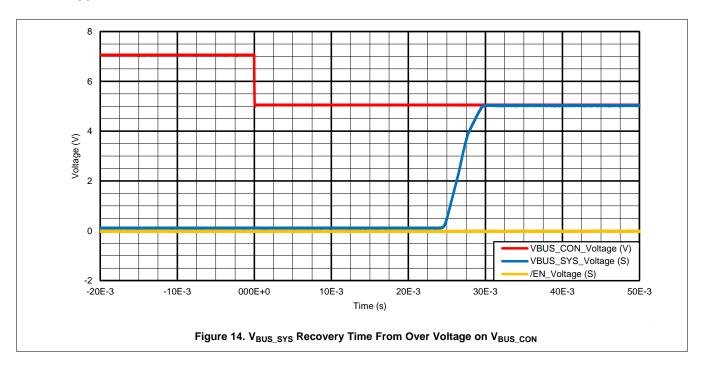
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9.2.2.2.3 Discharged Battery

Powering the PMIC from V_{BUS_POWER} allows logic control of the \overline{EN} pin to set TPD1S514-1 active and begin charging the battery and powering up the rest of the system.

9.2.2.3 Application Curves



10 Power Supply Recommendations

The TPD1S514 Family is designed to receive power from a USB 3.0 (or lower) V_{BUS} source. It can operate normally (nFET ON) between a minimum 3.5 V and a maximum V_{OVP_MIN} V. Thus, the power supply (with a ripple of V_{RIPPLE}) requirement for the TPD1S514 Family of devices to be able to switch the nFET ON is between 3.5 V + V_{RIPPLE} and V_{OVP_MIN} – V_{RIPPLE} , where V_{OVP_MIN} is:

| Device Name | V _{OVP_MIN} |
|-------------|----------------------|
| TPD1S514-1 | 5.90 V |
| TPD1S514-2 | 9.9 V |
| TPD1S514-3 | 13.5 V |
| TPD1S514 | 5.90 V |

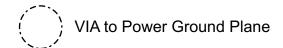


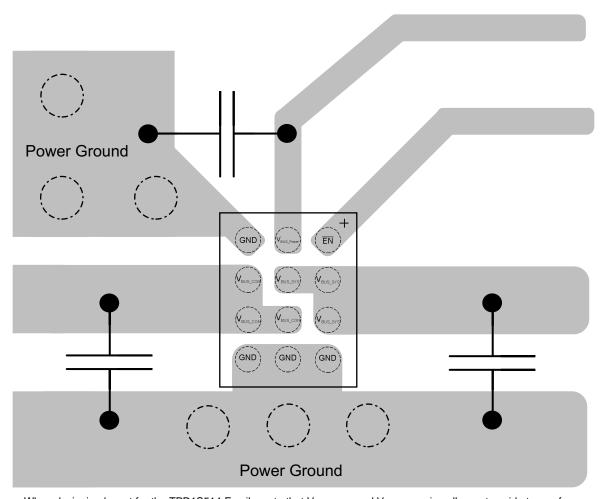
11 Layout

11.1 Layout Guidelines

- The optimum placement is as close to the connector as possible.
 - EMI during an ESD event can couple from the trace being struck to other nearby unprotected traces, resulting in early system failures.
 - The PCB designer needs to minimize the possibility of EMI coupling by keeping any unprotected traces away from the protected traces which are between the TVS and the connector.
- Route the protected traces as straight as possible.
- Eliminate any sharp corners on the protected traces between the TVS and the connector by using rounded corners with the largest radii possible.
 - Electric fields tend to build up on corners, increasing EMI coupling.

11.2 Layout Example





When designing layout for the TPD1S514 Family, note that V_{BUS_CON} and V_{BUS_SYS} pins allow extra wide traces for good power delivery. In the example shown, these pins are routed with 50 mil (1.27 mm) wide traces. Place the V_{BUS_CON} , V_{BUS_SYS} , and V_{BUS_POWER} capacitors as close to the pins as possible. Use external and internal ground planes and stitch them together with VIAs as close to the GND pins of TPD1S514 as possible. This allows for a low impedance path to ground so that the device can properly dissipate any surge or ESD events.

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12 Device and Documentation Support

12.1 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.2 Trademarks

E2E is a trademark of Texas Instruments.

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12.3 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.4 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

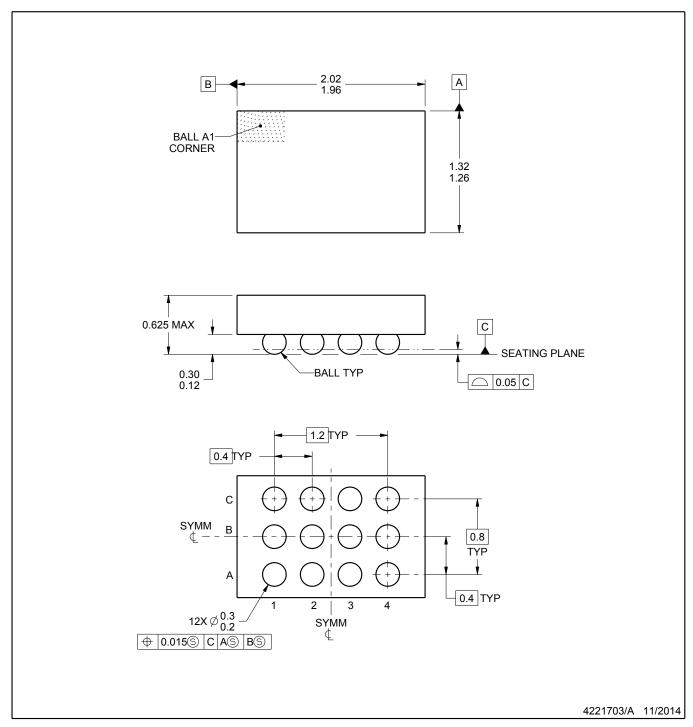
13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



DSBGA - 0.625 mm max height

DIE SIZE BALL GRID ARRAY



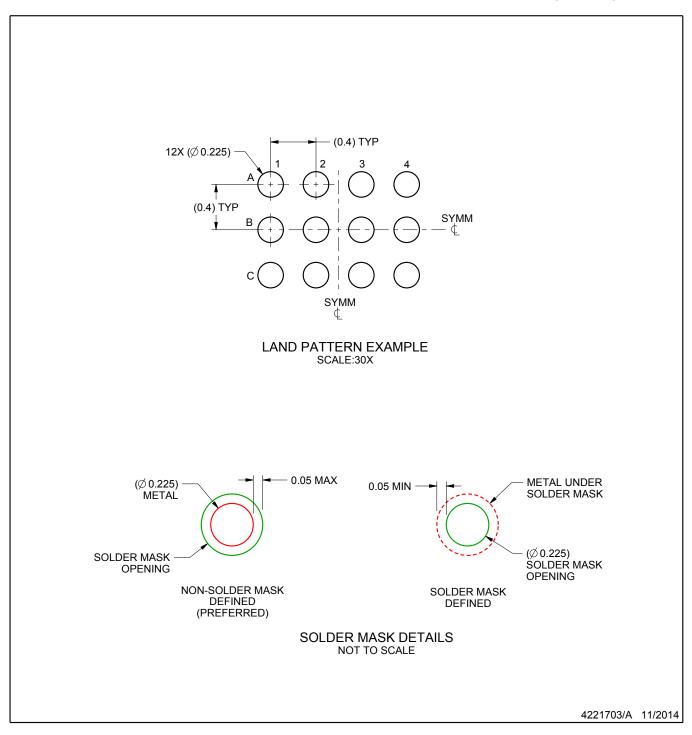
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.



DIE SIZE BALL GRID ARRAY

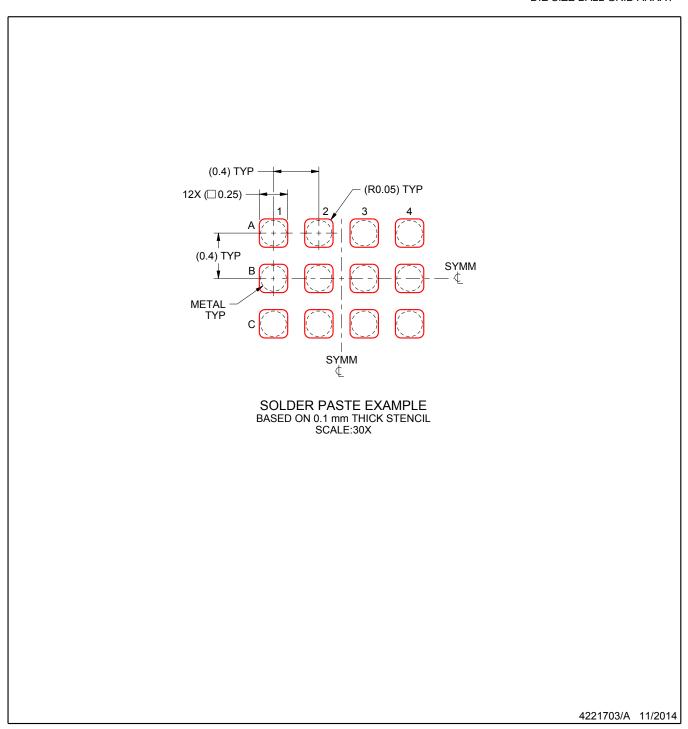


NOTES: (continued)

3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SBVA017 (www.ti.com/lit/sbva017).



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.





PACKAGE OPTION ADDENDUM

1-Dec-2015

PACKAGING INFORMATION

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| Orderable Device | Status | Package Type | _ | Pins | • | Eco Plan | Lead/Ball Finish | MSL Peak Temp | Op Temp (°C) | Device Marking | Samples |
|------------------|--------|--------------|---------|------|------|----------------------------|------------------|--------------------|--------------|----------------|---------|
| | (1) | | Drawing | | Qty | (2) | (6) | (3) | | (4/5) | |
| TPD1S514-1YZR | ACTIVE | DSBGA | YZ | 12 | 3000 | Green (RoHS & no Sb/Br) | SNAGCU | Level-1-260C-UNLIM | -40 to 85 | RH5141 | Samples |
| TPD1S514-2YZR | ACTIVE | DSBGA | YZ | 12 | 3000 | Green (RoHS & no Sb/Br) | SNAGCU | Level-1-260C-UNLIM | -40 to 85 | RH5142 | Samples |
| TPD1S514-3YZR | ACTIVE | DSBGA | YZ | 12 | 3000 | Green (RoHS & no Sb/Br) | SNAGCU | Level-1-260C-UNLIM | -40 to 85 | RH5143 | Samples |

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

1-Dec-2015

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PACKAGE MATERIALS INFORMATION

www.ti.com 19-Aug-2016

TAPE AND REEL INFORMATION





| A0 | <u> </u> |
|----|---|
| B0 | Dimension designed to accommodate the component length |
| K0 | Dimension designed to accommodate the component thickness |
| W | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

| Device | Package Type | Package Drawing | | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|---------------|-----------------|--------------------|----|------|--------------------------|--------------------------|------------|------------|------------|------------|-----------|------------------|
| TPD1S514-1YZR | DSBGA | YZ | 12 | 3000 | 180.0 | 8.4 | 1.39 | 2.09 | 0.75 | 4.0 | 8.0 | Q2 |
| TPD1S514-3YZR | DSBGA | YZ | 12 | 3000 | 180.0 | 8.4 | 1.39 | 2.09 | 0.75 | 4.0 | 8.0 | Q2 |

www.ti.com 19-Aug-2016



*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|---------------|--------------|-----------------|------|------|-------------|------------|-------------|
| TPD1S514-1YZR | DSBGA | YZ | 12 | 3000 | 182.0 | 182.0 | 20.0 |
| TPD1S514-3YZR | DSBGA | YZ | 12 | 3000 | 182.0 | 182.0 | 20.0 |

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